## Laser Assisted Particle Removal



- Photochemical reactive removal
- Photo- + thermochemical reactive removal

- Particle
- deformationSubstrate deformation
- Energy transfer medium explosive evaporation

Fig. 1

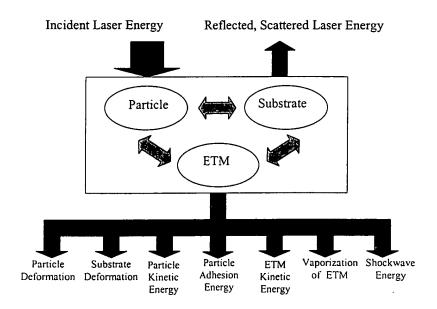


Fig. 2

Absorption Medium	Particle	ETM	Substrate with ETM	Substrate without ETM
Removal Mechanism	Rapid thermal expansion of particle	Explosive evaporation of ETM	Microbubble   formation at   liquid/solid interface	Rapid thermal expansion of the substrate
wavelength	λ< <particle diameter<="" td=""><td>λ&gt;&gt;Particle Diameter</td><td>λ&gt;Particle Diameter</td><td>λ&gt;&gt;Particle Diameter or λ<particle diameter="" if="" α<sub="">particle is low</particle></td></particle>	λ>>Particle Diameter	λ>Particle Diameter	λ>>Particle Diameter or λ <particle diameter="" if="" α<sub="">particle is low</particle>
Energy Absorption	α <sub>particle</sub> >>α <sub>substrate</sub>	High α <sub>ετΜ</sub>	High α <sub>substrate</sub>	High α <sub>substrate</sub>
Substrate Damage	-Melting/Ablation of particle	Shockwave, substrate absorption	-Melting/Ablation of particle or substrate -Shockwave in ETM	Melting/Ablation of particle or substrate
Particle Removal Threshold	$Φ_{th}$ =0.01-0.08 J/cm <sup>2</sup> $I_{th}$ =1-11 MW/cm <sup>2</sup> D=20 μm	$\Phi_{th}$ =0.65-2.2 J/cm <sup>2</sup> $I_{th}$ =3-11 MW/cm <sup>2</sup>	$\Phi_{th}$ =0.02-0.3 J/cm <sup>2</sup> $l_{th}$ =2-600 MW/cm <sup>2</sup> $\tau$ =0.03-20 ns	$\Phi_{th}$ =0.02-0.3 J/cm <sup>2</sup> $I_{th}$ =1-30 MW/cm <sup>2</sup> $\tau$ =7-30 ns

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Fig. 3

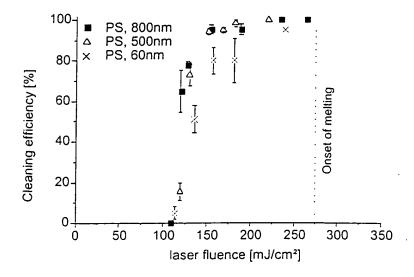


Fig. 4

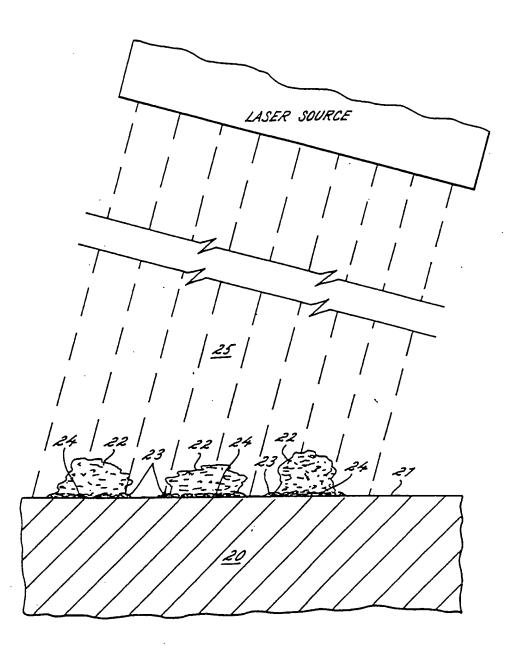
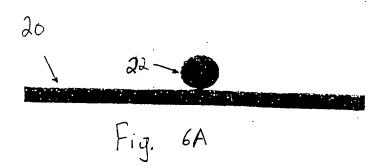
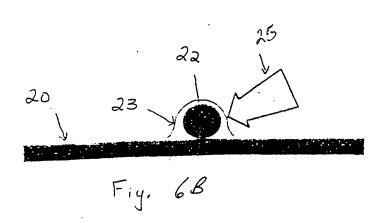


FIG. 5





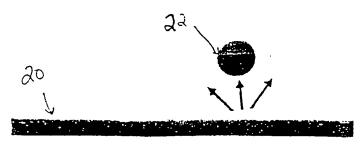


Fig. 6C

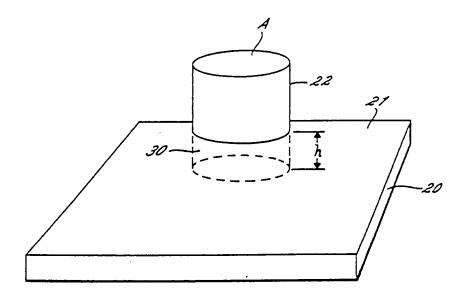
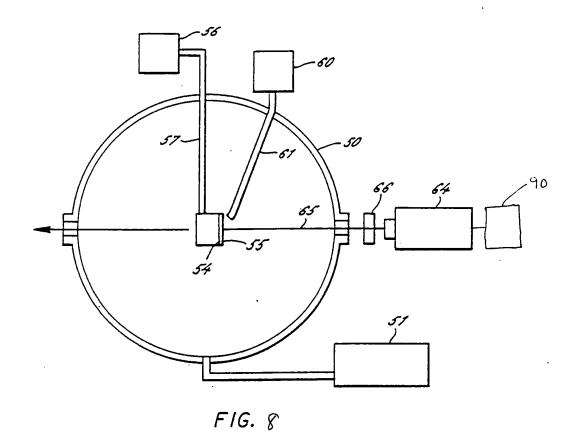
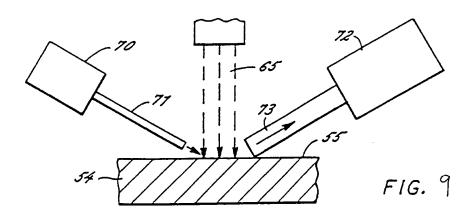
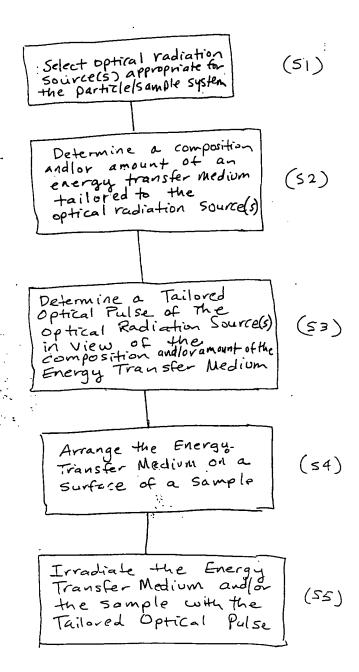


FIG. 7







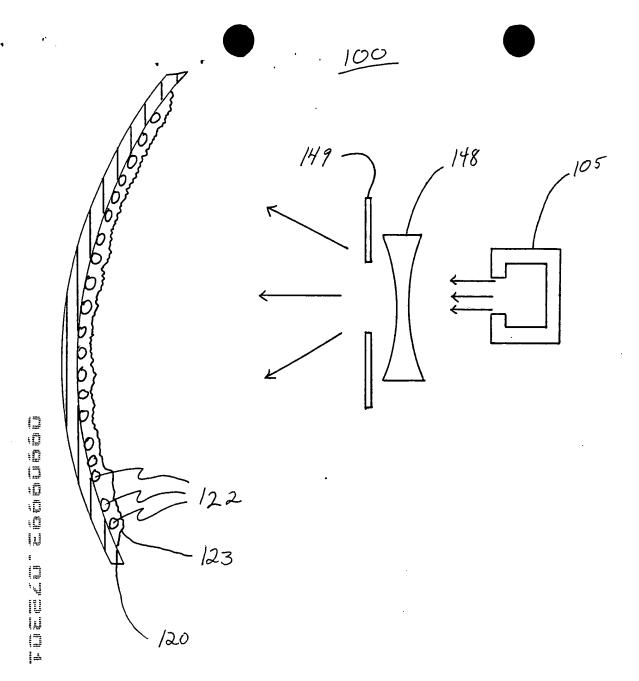


Fig. 11

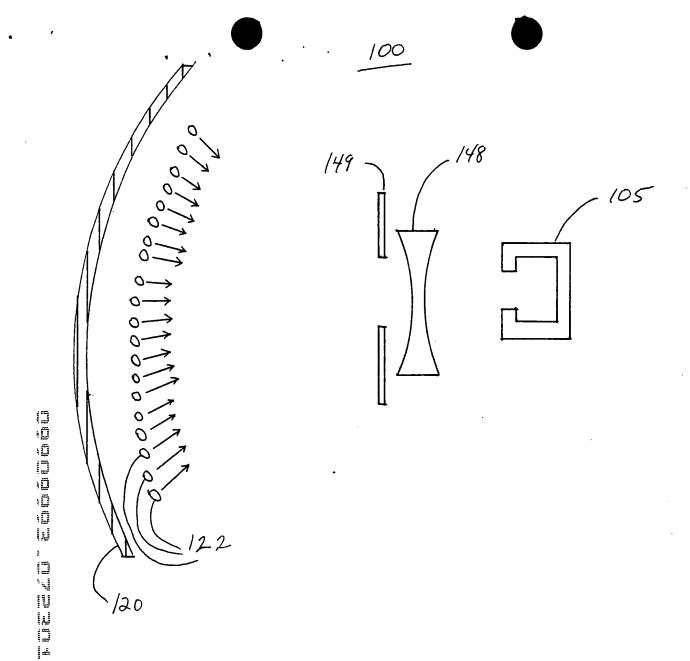


Fig 12

200

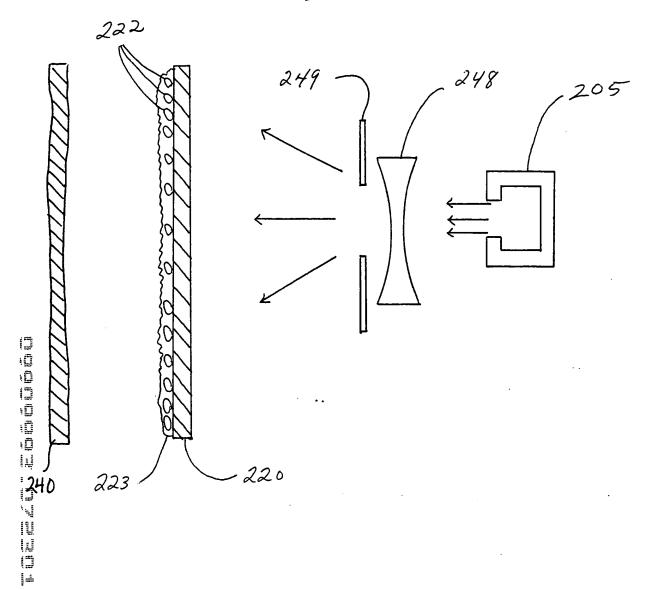


Fig 13